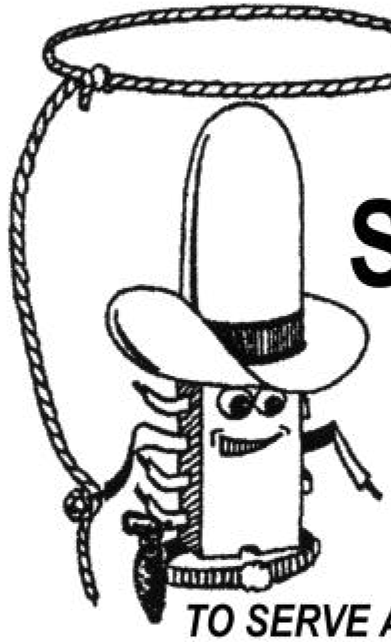

SOUTHWEST TEST WORKSHOP

TO ADVANCE WAFER TESTING TECHNOLOGY

TO SERVE AND INFORM THE WAFER TEST PROFESSIONAL

TO BOLDLY GO WHERE NO OTHER WORKSHOP HAS GONE BEFORE

June 1 – 4, 1997 San Diego, CA

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WHAT IS A TEST WORKSHOP?

- It’s not a theoretical or academic conference
- Workshops are informal and casual
- Provides practical solutions to real problems
- Mixture of vendor and user presentation
- Open discussions and networking
- Opportunity for informal discussions

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Test Technology Periodicals

- **International Test Conference Proceedings**
- 655 15th St., N.W., Suite 300
- Washington, D.C. 20005

- **Test Technology Technical COMMITTEE**
- Newsletter
- P.O. Box 629
- Hollidaysburg, PA 16648

- **Journal of Electronic Testing**
- Kiuwer Academic Publishers
- 101 Philip Drive
- Norwell, MA 02061

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- **Design and Test of Computers**
- IEEE Computer Society
- 10662 Los Vagneros Circle
- Los Alamitos, CA 90720-1314

- **Final Test Report**
- Ikonix Corporation
- P.O. Box 1938
- Lafayette, CA 94549

- **Evaluation Engineering**
- Nelson Publishing
- 2504 N. Tamiami Trail
- Nokomis, FL 34275-3482

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Dilip Wadhwani	Intel	602-715-1128

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Southwest Test Workshop - Attendee List

Dallas Wallace	Silicon Systems, Inc.	408-429-4795
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Christopher West	inTEST Corp.	609 424-6886
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Welton Whann	Micro-Probe, Inc.	619-603-0631
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Jack Willett	Analog Devices	617-937-2718
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Ralph Williams	Technology To Go	408-578-6256
Irv Wilson	ESH Inc.	602 438-1112
Mark Winn	Intel	505-893-0576
Steven Wolf	Chip Supply, Inc.	407-298-7100
David Woodliff	Motorola	512-505-8363
Kunihiro Yamazaki	ATE Service Co., Inc.	81-423-77-8811
Yuki Yoshida	TSK America	512-834-4344
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John Zimmel	Wentworth	203-775-9311
Karl Zimmermann	Contact Technologies	805 498-8157
Rob Zokaei	Probe Technology	408-980-1740
Marek Zywno	Electroglas	408-727-6500 x6594

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• RF Wafer Probing

“Microwave Probing”
Jim Bossaller
Hewlett Packard, MS 3USQ

“High Frequency Basics”
Tom Strouth
GigaTest Labs Inc.

• Automatic Probe Mark Inspection on Probers

“Electroglas EG4090”
Dai Dee Casavant
Electroglas

“TEL P8”
Marius Lupan
Tokyo Electron America

“TSK APM 90A”
Earl Eddy
TSK America

• Prober -Test Head Interface

“The Test Head Hoist – A New Concept in Test Head Positioning”
Marvin Weilerstein
Christopher West
InTest

“Design Concepts for a Total Integrated Solution”
Jim Anderson
Cerprobe Corporation

“Probe to Pad XY Scrub Positioning Process”
Al Miller
Digital Micro Electronics, HL01-109

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